

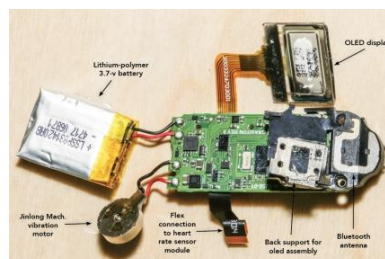
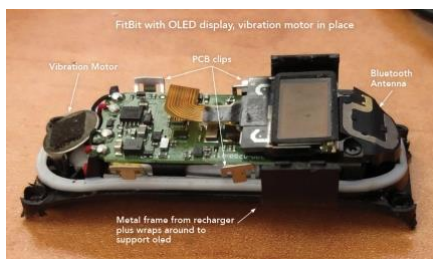
PACKAGING OF INTELLIGENT SYSTEMS

Prof. Vivek Subramanian

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Modern Integrated Systems

- Silicon is king for integrating intelligence
- Lots of sensors and physical world interfaces
- Energy needs strongly impact form factor



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Discussion Topic 1

What are the constraints impacting packaging of systems containing the following:

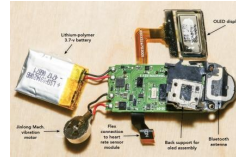
- Display / Touch Screen
- Battery
- Microprocessors
- Memory

INTEGRATION OF INTELLIGENCE

Hierarchical Assembly – what and why?

- Building systems by combining components with varying complexity to produce a highly integrated system
- Why?

| | | |
|-----|----------------------------------|--------------|
| 1. | Hong Kong, Hong Kong | 31,943.48 \$ |
| 2. | Singapore, Singapore | 20,246.07 \$ |
| 3. | Seoul, South Korea | 17,242.85 \$ |
| 4. | New York, NY, United States | 15,886.00 \$ |
| 5. | Beijing, China | 15,432.14 \$ |
| 6. | Shenzhen, China | 14,776.70 \$ |
| 7. | London, United Kingdom | 14,683.78 \$ |
| 8. | Geneva, Switzerland | 14,471.10 \$ |
| 9. | Paris, France | 14,382.89 \$ |
| 10. | Shanghai, China | 14,313.12 \$ |
| 11. | Zurich, Switzerland | 14,145.98 \$ |
| 12. | San Francisco, CA, United States | 13,676.87 \$ |
| 13. | Tel Aviv-Yafo, Israel | 13,580.74 \$ |
| 14. | Macao, Macao | 13,462.27 \$ |
| 15. | Brooklyn, NY, United States | 13,199.25 \$ |
| 16. | Taipei, Taiwan | 13,174.10 \$ |
| 17. | Munich, Germany | 12,904.45 \$ |
| 18. | Lausanne, Switzerland | 12,352.54 \$ |
| 19. | Basel, Switzerland | 12,334.20 \$ |
| 20. | Lugano, Switzerland | 12,325.03 \$ |
| 21. | Luxembourg, Luxembourg | 11,750.16 \$ |
| 22. | Tokyo, Japan | 11,701.39 \$ |



Silicon wafer cost: ~\$10,000 for a 300mm diameter wafer
Area: ~70,000 mm²
Cost: ~\$150,000 per m²

Precision hierarchy:
On-wafer (transistors): 2nm
On-wafer (wiring): 100nm
Wafer-to-package: 1μm
Package: 10μm
Board: 100μm

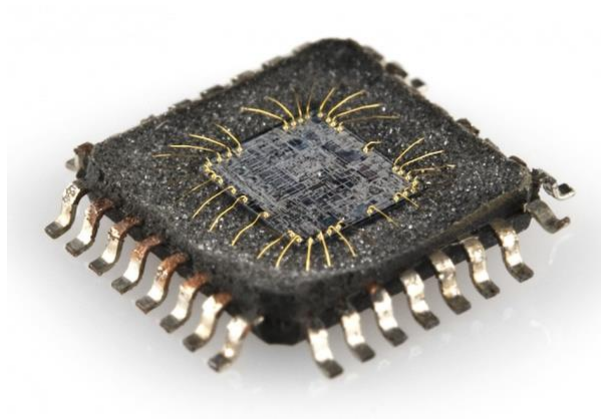
It is expensive to build a robot that can move large distances at high-precision. Therefore, it is better to do things in a hierarchy of assembly

The hierarchy in microelectronics



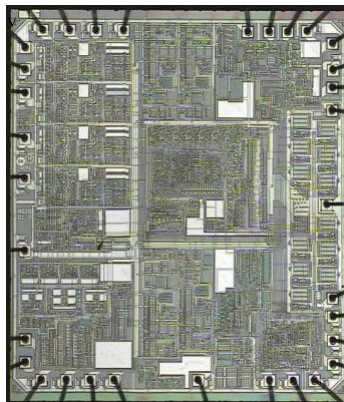
The Board Level

The hierarchy in microelectronics



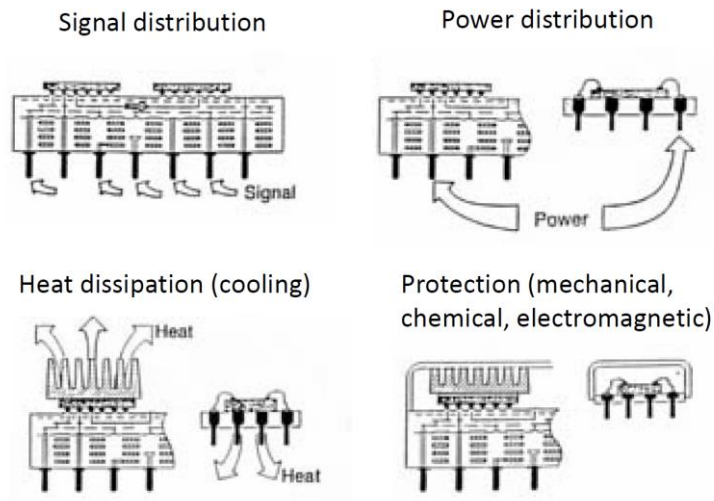
Inside the chip package

The hierarchy in microelectronics

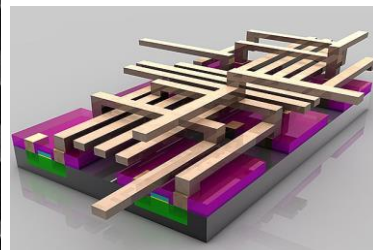
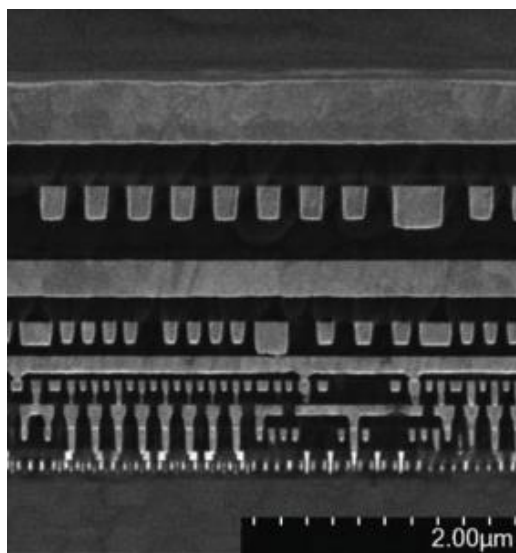


The semiconductor Die

Packaging of silicon integrated circuits – why?



Cross-section of a microprocessor

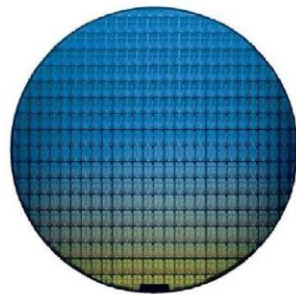


Questions to consider

- What is the peak process temperature that such a wafer can be subjected to? Why?
 - HINT: Consider the materials inside the fully fabricated chip

Chip Packaging Process Flow Major Steps

1. Wafer Preparation



Silicon Wafer

- Silicon wafer are mounted on a laminating tape that adheres to the back of the wafer
- The laminating tape holds the wafer throughout the dicing and the die attaching process

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Chip Packaging Process Flow Major Steps

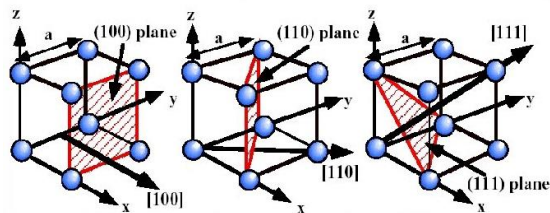
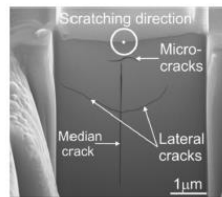
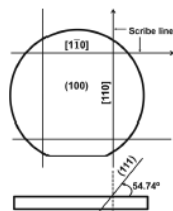
2. Dicing



- Die-sawing machine using a diamond saw blade cuts the wafer into individual die/pellet
- CO₂ gas bubbles are dispensed on the wafer to remove silicon dust/debris & lubricating and cooling down the blade

Die singulation Technologies – Scribing / Cleaving

- A “scratch” is made along a crystal plan, and upon application of mechanical pressure, the wafer cleaves along the plane



Discussion: Advantages and disadvantages of cleaving

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Singulation Technology: Sawing

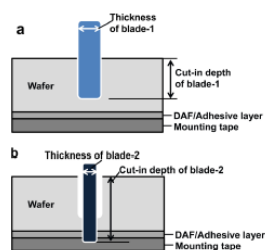


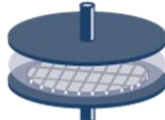


FIG. 6. (Color online) Schematic two-step blade dicing process. (a) Step 1: dicing partially into wafer substrate; (b) step 2: dicing into mounting tape.

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Singulation Technology: Laser and Plasma cutting

Technologies for semiconductor wafer dicing

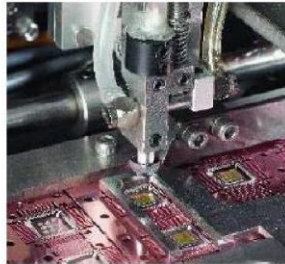
| Method | Blade | Laser | Plasma |
|-------------------------|---|---|--|
| Schematic |  |  |  |
| Procedure | Cuts through wafer using abrasive blade | Creates cracks using laser heat to split wafer | Etches away wafer using chemical reaction |
| Speed | ✗ Tens of millimeters per second | △ Hundreds of millimeters per second | ○ Entire wafer processed all at once |
| Chip fracture toughness | ✗ Mechanically damaged | ✗ Mechanically damaged | ○ No mechanical damage |
| Dryness | ✗ Uses water for cutting | ○ Dry process | ○ Dry process |

General Considerations during singulation

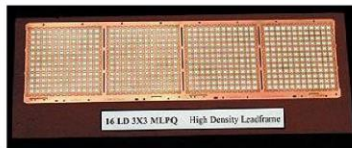
- Size of kerf
- Chipping
- Die sidewall damage
- Surface contamination
- ESD
- Delamination
- Intra-die defects

Chip Packaging Process Flow Major Steps

3. Die Attach



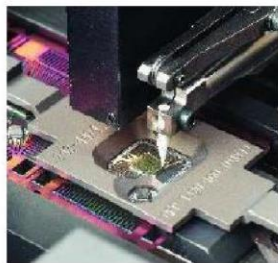
- The die attach machine will pick up the die and deposit it on the lead frame.
- It may utilize the wafer mapping method to pick up only good die.



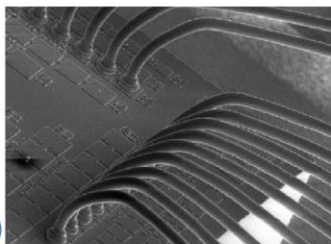
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Chip Packaging Process Flow Major Steps

4. Wire Bonding



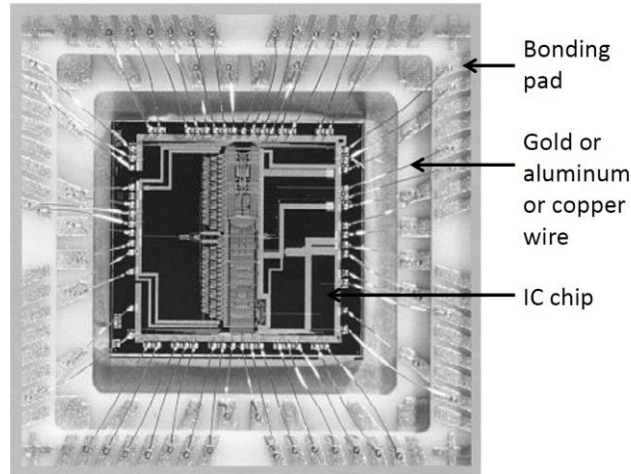
- Either Au or Al wires are used depending on application.
- Bonded one at a time, the wire is fed through a ceramic capillary.
- With a good combination of temperature and ultrasonic energy, a good metalized wire bond is formed



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Chip Packaging Process Flow Major Steps

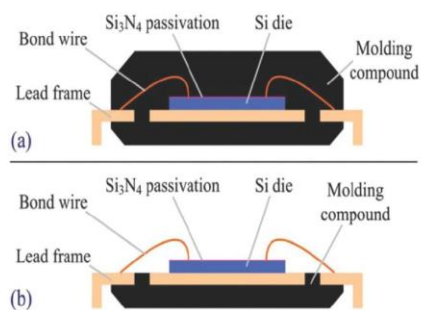
Wire-bonding



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Chip Packaging Process Flow Major Steps

5. Moulding

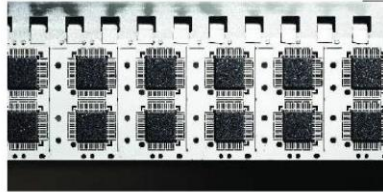


- The moulding process aims to encapsulate the whole wire bonded die against exposure to contamination and other physical damages.
- The lead frames that hold the dies are placed in individual cavities which are filled with liquid resin.

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Chip Packaging Process Flow Major Steps

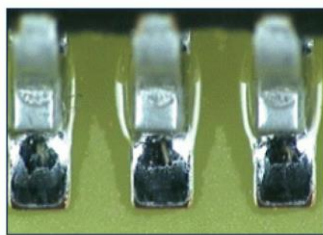
6. Solder Plating



- This step provides a layer of Tin Lead solder on the lead frame for making easier the PCB assembly process.
- Lead free finishing with Tin Bismuth plating or Tin Copper dipping can also be used.

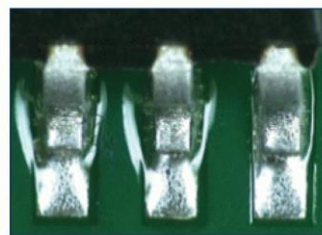
Solder Choices

Leaded VS Lead-Free Solder



63/37 Solder in air

Leaded Solder:
-Tin-lead (Sn63Pb37)
-melting point ~183 °C
-shiny & smooth surface



SAC Solder in air

Lead-Free Solder:
-Tin-Silver-Copper (SnAgCu)
-melting range of 217–220°C
-slightly grainy surface
Others: SnCu



What is a solder

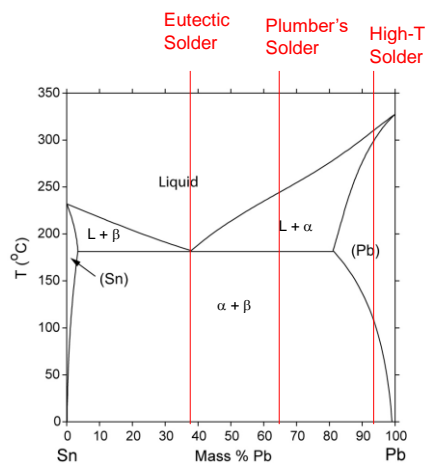
- Fundamentally, a solder is a low-melting-temperature conductive material (typically a metal alloy)
 - Low temperature to ensure package and PCB compatibility
 - Conductive to deliver low interconnection resistance
 - Wettability to ensure good contact to pads on both sides
 - Chemical and thermal stability (including dissolution of pads) for reliability
- Most important solders are based on tin alloys

Selected solder prices in 2015 [72].

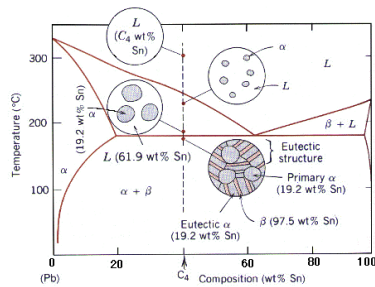
| Alloy | \$US/kg (approx.) |
|-------------------|-------------------|
| Sn37Pb | 14 |
| Sn9Zn | 21 |
| Sn5Sb | 21 |
| Sn56Bi | 17 |
| Sn0.7Cu | 21 |
| SA1305 | 41 |
| Sn2Ag0.5Cu7.5Bi | 34 |
| Sn2.5Ag0.8Cu0.5Sb | 37 |
| Sn3.5Ag3Bi | 44 |
| Sn3.4Ag4.8Bi | 43 |
| Sn3.5Ag | 44 |
| Sn4Ag0.5Cu | 47 |
| Sn3.5Ag1.5In | 50 |
| Sn2.8Ag20In | 118 |

The classic solder: Pb-Sn

- How do we choose the alloy ratio?



How to consider solidification of solder



Consider a 40 wt% Sn-60 wt% Pb alloy on the phase diagram.

Part 1:

- At 183.1 degrees C, just above the eutectic line, what phase(s) is (are) present?

Find the point corresponding to 40 wt% Sn and 183.1 degrees C on the diagram. It lies in an alpha + liquid region. Therefore both the alpha phase and the liquid phase are present.

- what is (are) the compositions of the phase(s)?

Extend a horizontal line from this point to the closest phase boundaries. The composition of the liquid phase is 61.9 wt% Sn and the composition of the alpha phase is 19.2 wt% Sn.

Part 2:

- Now, the temperature is lowered slightly to right below the eutectic line at 182.9°C. What is the composition of each phase?

Drop the lines from the intersections as before to discover that the composition of the alpha phase is 19.2 wt% Sn and the composition of the beta phase is 97.5 wt% Sn.

General choices for adding to Tin

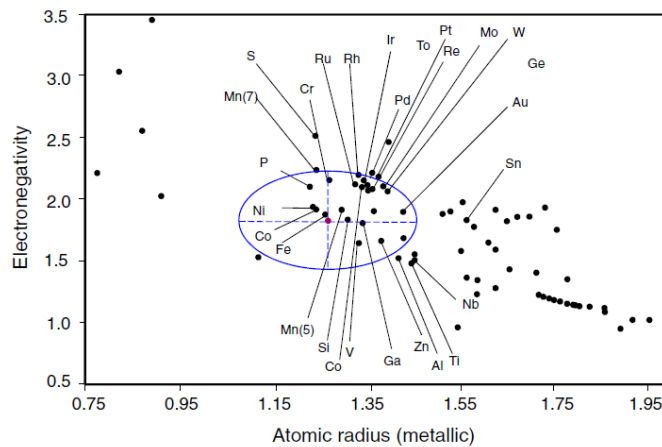
| Element | Melting temperature (°C) | Characteristics | Antimony (Sb) | 630.5 | <ul style="list-style-type: none"> Increases mechanical properties Slightly reduces thermal and electrical conductivity Considered toxic (listed on the EACEM list of "not to be used" substances) |
|--------------|--------------------------|---|----------------|-------|---|
| Tin (Sn) | 232 | <ul style="list-style-type: none"> Base alloy metal Low melting temperature Readily available Tin whiskers and tin pest are problematic | Gold (Au) | 1063 | <ul style="list-style-type: none"> Increases melting temperature Issues with gold embrittlement with increasing gold content |
| Bismuth (Bi) | 271.5 | <ul style="list-style-type: none"> Lowers melting temperature Higher tensile strength Increases brittleness and prone to thermal fatigue Expands on solidification When contaminated with lead, becomes more brittle | Cadmium (Cd) | 321.1 | <ul style="list-style-type: none"> Very expensive Cadmium and its compounds are listed in the RoHS directive and therefore are considered hazardous substances. To comply with restrictions, cadmium should not be used in alternative lead-free solder joints. |
| Copper (Cu) | 1084 | <ul style="list-style-type: none"> Some toxicity concerns in animals Inexpensive and affected the least by lead impurities | Silver (Ag) | 962 | <ul style="list-style-type: none"> Absorbs Cu, intermetallic growth with Cu Expensive Inhibits Cu dissolution |
| Indium (In) | 156.6 | <ul style="list-style-type: none"> Oxide layer is more difficult to remove Lowers melting temperature Very expensive and scarce Extremely soft and lacks mechanical strength in alloys with high indium contents Corrosion-prone | Nickel (Ni) | 1453 | <ul style="list-style-type: none"> Can improve the shear ductility of SAC solders |
| Zinc (Zn) | 419.5 | <ul style="list-style-type: none"> Fast oxide formation during melting Oxides and corrodes readily Requires strong fluxes | Chromium (Cr) | 1857 | <ul style="list-style-type: none"> Can suppress void formation and coalescence at the Cu/Cu₃Sn interface |
| | | | Iron (Fe) | 1535 | |
| | | | Manganese (Mn) | 1245 | |
| | | | Silicon (Si) | 1410 | <ul style="list-style-type: none"> Can inhibit growth of Cu₃Sn and Kirkendall voids in the Cu/SnAgCu system |
| | | | Titanium (Ti) | 1660 | |
| | | | Palladium (Pd) | 1552 | <ul style="list-style-type: none"> Can dissolve to Cu sublattice of Cu₆Sn₅ |
| | | | Platinum (Pt) | 1772 | |

Pb-Free Solders

Table 4
Lead-free solder bump compositions [82].

| Composition (wt%) | Melting point (°C) | Applications | Concerns |
|---|--------------------|--|---|
| SnAg (e.g., Sn3.5Ag, Sn2.3Ag, Sn1.8Ag) | ~221 | SMT, flip chip Currently the most common binary lead-free solder for flip chip. Typically used in conjunction with electroplating | Cu dissolution, excessive IMCs, voids |
| SnCu (e.g., Sn0.7Cu, Sn3Cu) | ~227 | PTH, flip chip | Cu dissolution, wetting, excessive IMCs |
| SAC (e.g., SAC305, Sn3.8Ag0.7Cu, Sn3.9Ag0.6Cu) | ~217 | SMT, PTH, BGA, flip chip (limited), SOP | Cu dissolution, excessive IMCs, voids |
| Sn80Au | 280 | Flip chip Common for flux-free opto-electronic assembly on gold finishes, controlled standoff height | High cost |
| Sn | 232 | Flip chip | Tin whiskers |

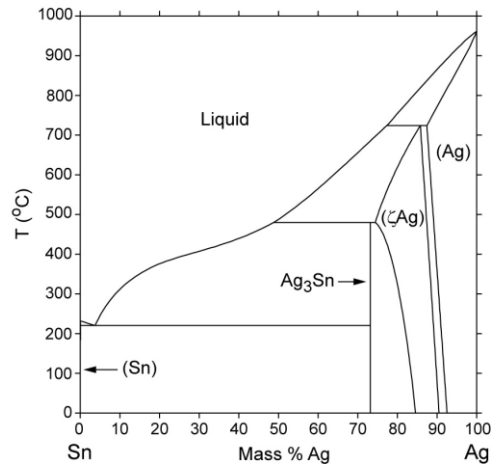
Cu solubility



Darken-Gerry plot... atoms with similar electronegativity and radius will typically show higher solid solubility

Sn-Ag

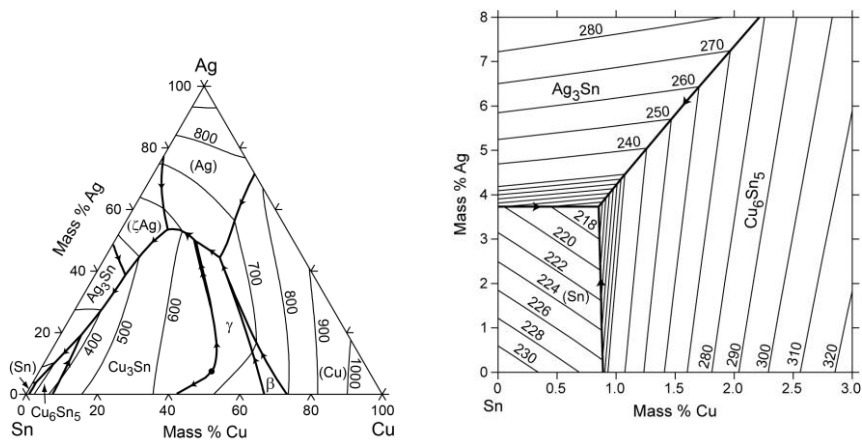
- What are the key advantages / disadvantages?



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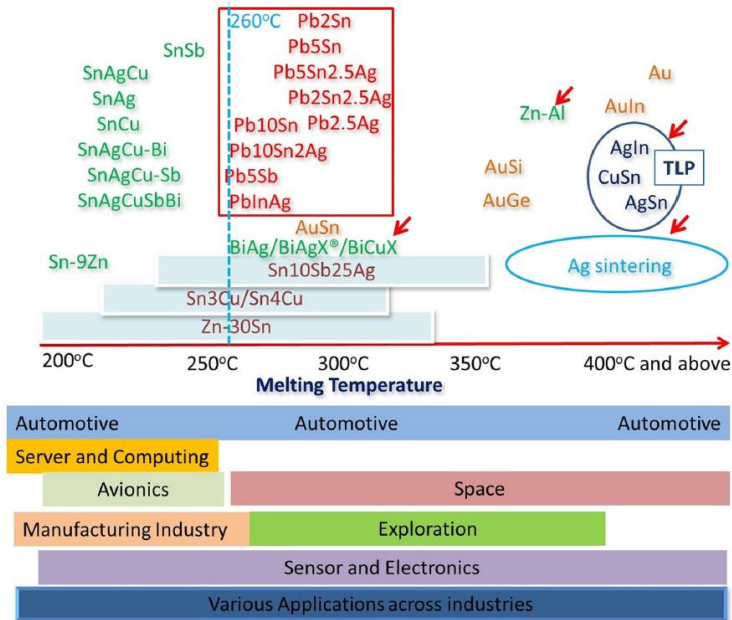
The Sn-Ag-Cu system

- Why?



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Summary of Solder Choices



Chip Packaging Process Flow Major Steps

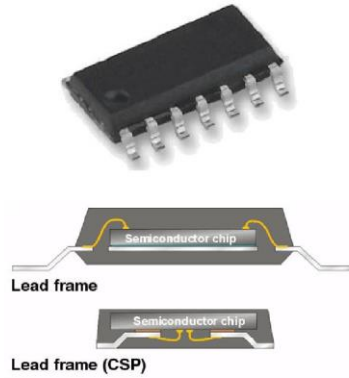
7. Marking



- Marking is the coding process that writes customer's corporate and product identification code on a packaged device.
- It commonly uses a laser-based machine

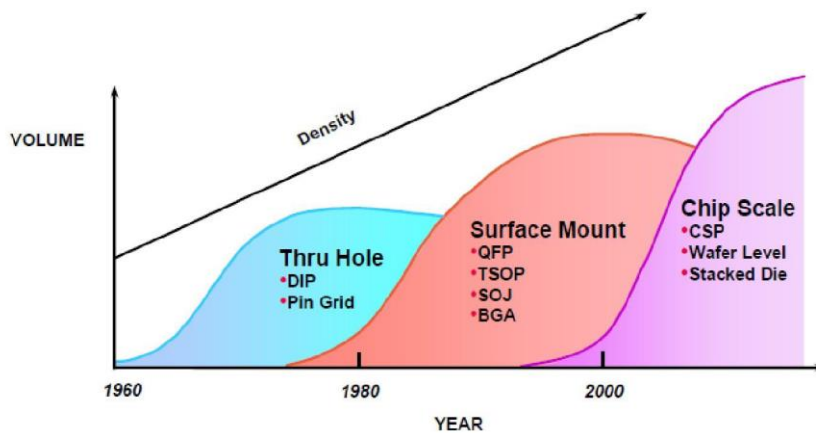
Chip Packaging Process Flow Major Steps

8. Lead Trim/ Form



- The final process is to trim away the leads of the packaged device from the frame strip.
- The leads are cut and formed mechanically to the specified shape

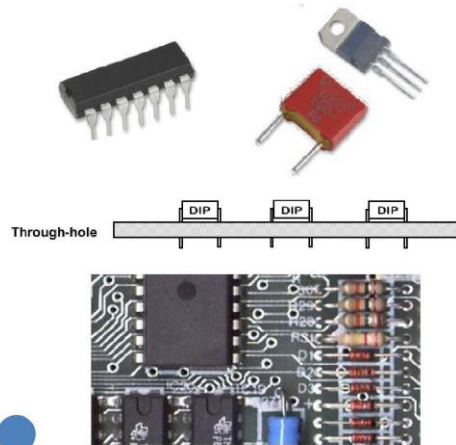
Packaging Trends over time?



Question: What was the major technology platform during each transition?

Packaging Wave 1: 1960s to today

1. Through-hole Mounting

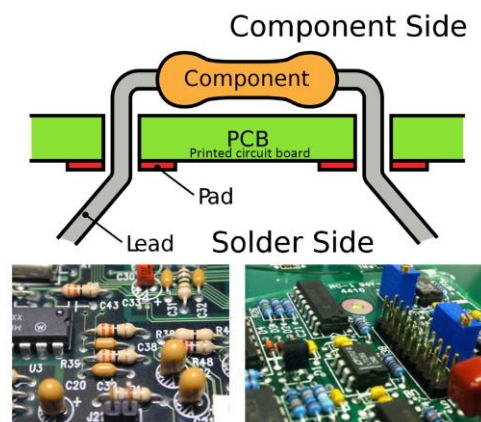


- Pins of the components go through the drilled printed circuit board (PCB) holes

Note:
DIP: dual in-line package

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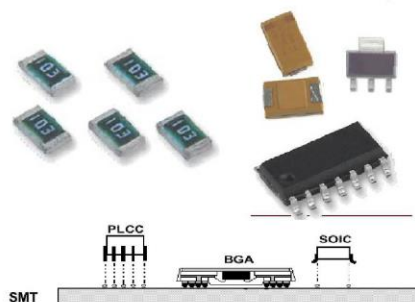
Packaging Wave 1: 1960s to today



What are the advantages / disadvantages of through-hole packaging?

Packaging Wave 2: 1980s to today

2. Surface-Mount Technology (SMT)

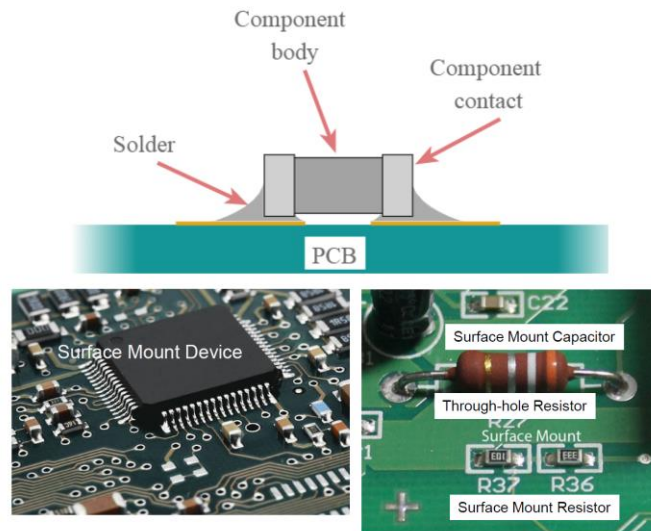


- The pins of the devices are mounted directly onto the surface of the PCB

Note:
PLCC: Plastic leaded chip carrier
BGA: Ball Grid Array
SOIC: Small Outline Integrated Circuit

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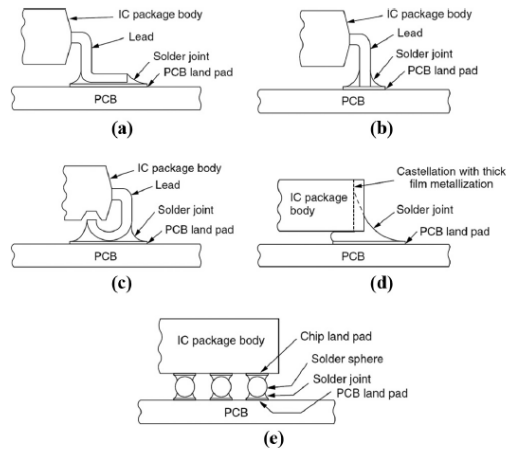
Packaging Wave 2: 1980s to today



What are the advantages / disadvantages of surface mounting?

Solder deposition processes for surface mount components

- General configurations



Notes: (a) gullwing; (b) butt-lead; (c) J-lead; (d) leadless metallization; (e) ball-lead

Solder deposition processes for surface mount components

Figure 3 Reflow soldering process

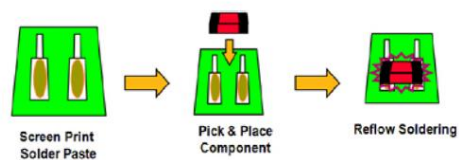
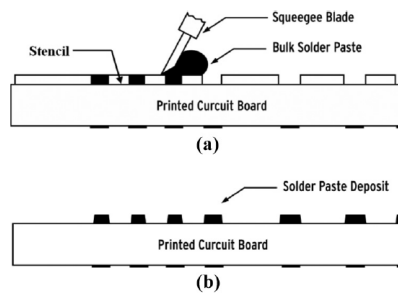
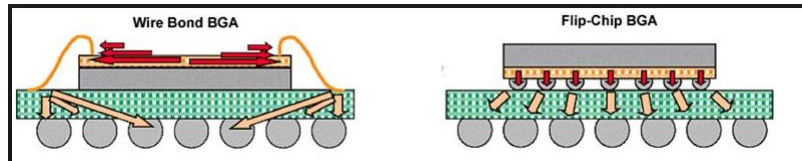


Figure 4 Stencil printing process



Major Chip Interconnection Types



Comparison Flip-chip vs wirebond

TABLE 1: PROCESS ADVANTAGES

WIRE BOND

- FLEXIBILITY
- INFRASTRUCTURE
- COST
- RELIABILITY

FLIP-CHIP

- DEVICE SPEED
- POWER AND GROUND DISTRIBUTION
- I/O DENSITY WITH AREA ARRAY
- PACKAGE SIZE/FORM FACTOR
- LOW STRESS OVER ACTIVE AREA
- RELIABILITY

TABLE 2: ASSEMBLY PROCESS COMPARISON ON ORGANIC SUBSTRATE

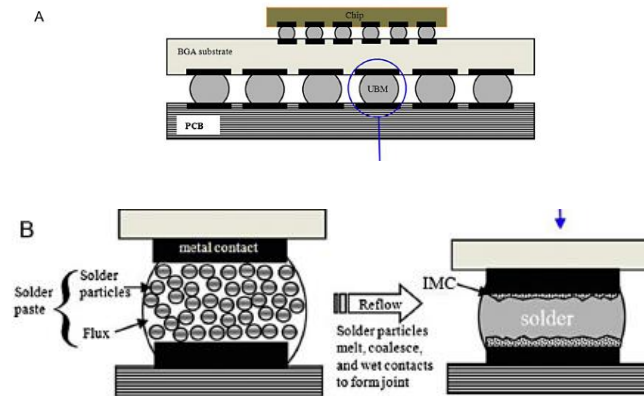
WIRE BOND

- WAFER
- DICE
- DIE ATTACH
- CURE
- WIRE BONDING
- ENCAPSULATE
- BALL ATTACH
- MARK
- SYSTEM TEST

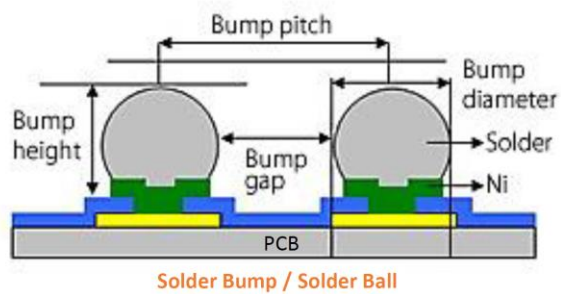
FLIP-CHIP

- WAFER
- WAFER BUMPING
- DICE
- PICK AND PLACE PLUS FLUX
- REFLOW
- UNDERFILL ENCAPSULATION
- BALL ATTACH
- MARK
- SYSTEM TEST

Solder Pastes



Dimensions in packaging



Question: Why do we need solder bumps?

Non-planarity and solders

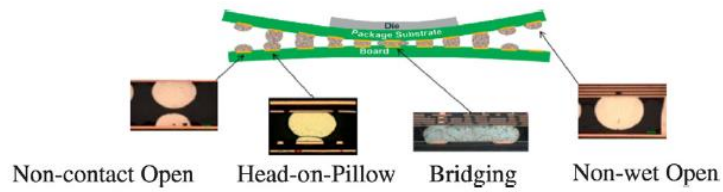

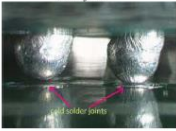

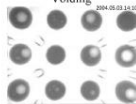
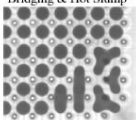
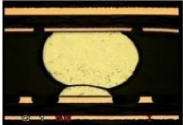



Fig. 5. Typical surface mount technology defects.

Preview: Exercise

- Develop a framework to estimate the amount of nonplanarity allowed as a function of pad density

Some defect types in solder ball packaging

| Defect type | Mechanism (s) | Defect type | Mechanism (s) |
|--|---|---|--|
| Cracking  | Too high an internal stress due to fast temperature change rate | Cold joint  | Insufficient coalescence |
| Tombstoning & Skewing  | Uneven wetting at both ends of chip | Voiding  | Excessive oxidation |
| Bridging & Hot Slump  | Viscosity drops with temperature | De-wetting  | Overheat at temperature above solder melting point |
| Opens  | Non-wetting due to oxidation | | |

Bump vs. Pillar

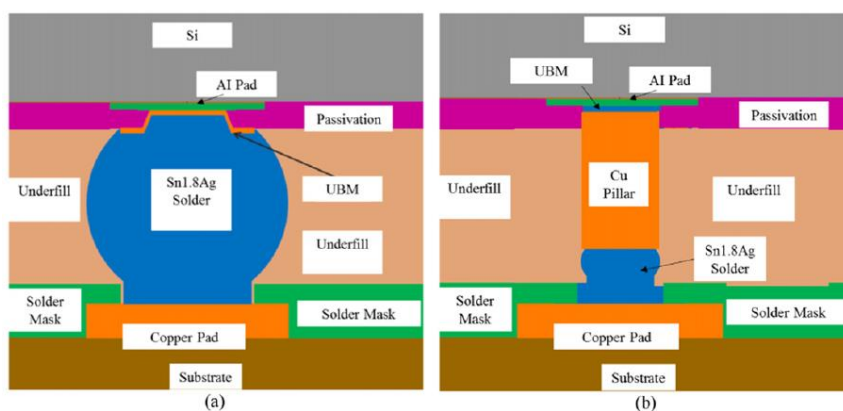
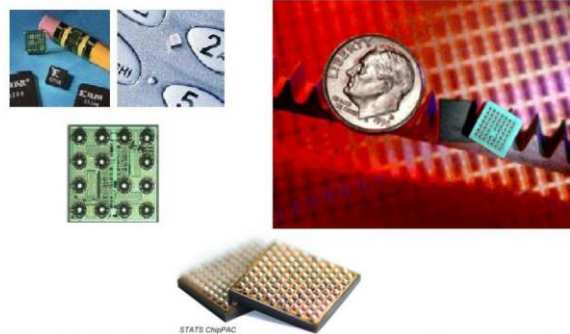


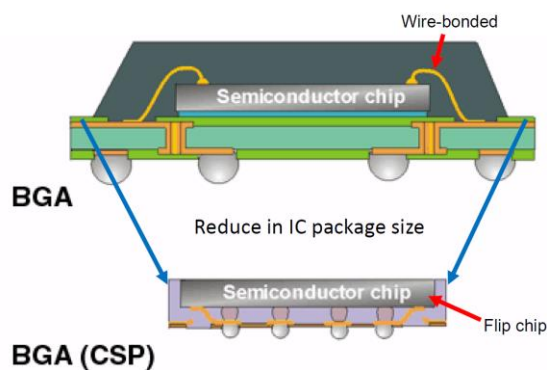
Fig. 7. Schematic of conventional (a) and Cu pillar (b) SnAg solder bumps [148].

3. Chip Scale Packages (CSP)



- CSP is single-die, direct surface mountable package
- Is an evolution of surface mount device (SMD)
- CSP come in many forms –flip chip, wire-bonded, ball grid array, leaded, etc.

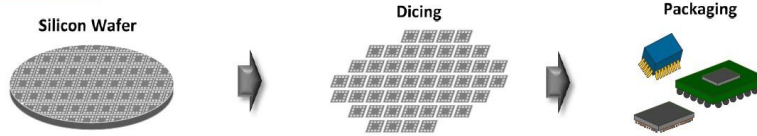
16



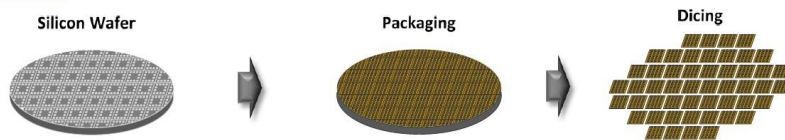
17

Packaging of Silicon Wafers

Traditional Packaging



WLCSP Packaging



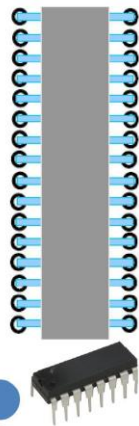
Density trends in packaging

Three Packaging Technologies: Summary

Through Hole

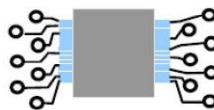
Surface Mount

CSP / WLP



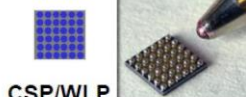
DIP

- 100 mil pitch
- Limited by through hole spacing



TSOP

- 25 mil pitch
- Limited by perimeter leads



CSP/WLP

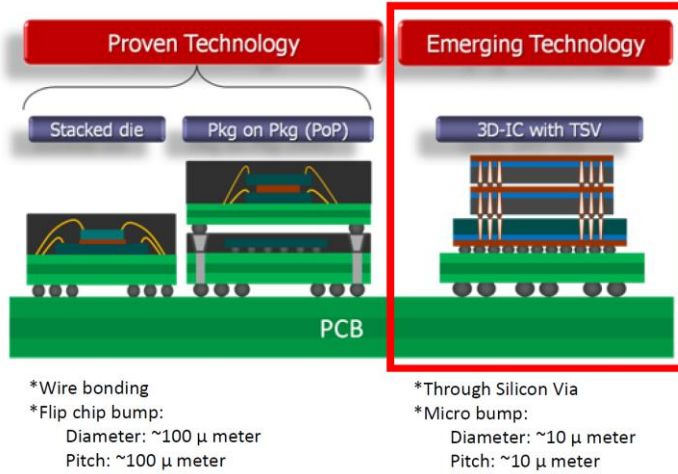
- Area array 0.8 mm to 0.5 mm
- Limited by substrate wiring

Note: 1 mil = 0.0254 mm

Note:
DIP: Dual-in-line package
TSOP: Thin Small Outline Package
WLP: Wafer level package

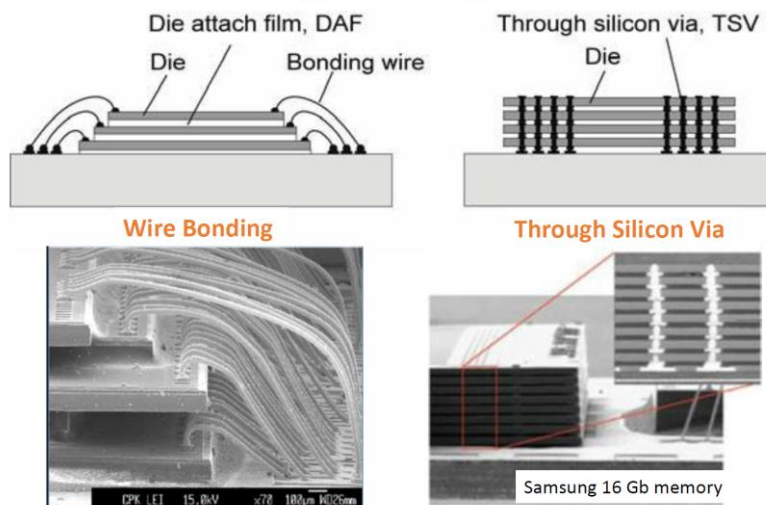
Chip Stacking: Enabling Wearables and Mobile

Recent IC Packaging Technology – 3D IC with TSV



Chip Stacking

Wire Bonding VS Through Silicon Via



Review Thought Exercise

- Design a wearable device for monitoring your sweat, focusing on component choices and impact on packaging